

<b>Notice of References Cited</b>	Application/Control No. 09/784,159	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Justin P. Misleh	Art Unit 2612	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,954,280 B1	10-2005	Kaibara, Hiroshi	358/1.15
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 944247 A2	09-1999	European Patent	NIKAWA et al.	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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